

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	24	scan\$4 near5 (signal or request) near9 (eras\$4 or delet\$4) near9 (password or identif\$7 or key or ((secret or sensitive) (data or info\$7)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 10:34
L2	20	scan\$4 near2 (test or set) same (delet\$4 or eras\$6) near9 (sesitive or secret or password or identification or "PID" or identifier or key)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:27
L3	5280	scan test	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:27
L4	6408	(scan test\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:27
L5	0	(scan test\$4) same delet\$4 near3 sensitive	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:28
L6	0	(scan test\$4) same delet\$4 near3 secret	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:28
L7	0	(scan test\$4) same delet\$4 near3 secret\$4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2008/01/03 11:28
S1	1133	"integrated circuit" same "scan test"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 13:59
S3	4	"integrated circuit" same "scan test" same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 14:07
S4	5	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same "scan test" same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 14:22

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S5	1	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same set\$1scan same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 14:23
S6	2	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same boundary\$1scan same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 16:02
S8	7	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (test near scan) same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 16:03
S10	1	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (set near scan) same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 16:04
S11	11	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (set near scan) and ((secur\$5 or protect\$4) same (sensitive or password or key))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/26 16:05
S13	20	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (scan near test) and ((secur\$5 or protect\$4) same (sensitive or password or key))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:15
S14	1688	713/193.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:10
S15	7	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same test near scan same security	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:15
S16	1429	714/726.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:15
S17	20	("integrated circuit" or "IC" or microcircuit or microchip or "silicon chip" or "computer chip") same (scan near test) and ((secur\$5 or protect\$4) same (sensitive or password or key))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:15

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S18	4	S16 and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:17
S19	2	S14 and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/02/27 09:17
S20	2	scan\$4 same ((sensitive or confidential or protected or secure) adj (data or information or info)) near9 (eras\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/07/29 13:48
S21	2	"5,305,383".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2007/07/29 13:48